# N-Channel UniFET II MOSFET

600 V, 4 A, 2 Ω

UniFET II MOSFET is ON Semiconductor's high voltage MOSFET family based on advanced planar stripe and DMOS technology. This advanced MOSFET family has the smallest on–state resistance among the planar MOSFET, and also provides superior switching performance and higher avalanche energy strength. In addition, internal gate–source ESD diode allows UniFET II MOSFET to withstand over 2 kV HBM surge stress. This device family is suitable for switching power converter applications such as power factor correction (PFC), flat panel display (FPD) TV power, ATX and electronic lamp ballasts.

#### **Features**

- $R_{DS(on)} = 1.65 \Omega$  (Typ.) @  $V_{GS} = 10 \text{ V}$ ,  $I_D = 2 \text{ A}$
- Low Gate Charge (Typ. 10 nC)
- Low C<sub>rss</sub> (Typ. 5 pF)
- 100% Avalanche Tested
- Improved dv/dt Capability
- ESD Improved Capability
- These Devices are Pb-Free and are RoHS Compliant

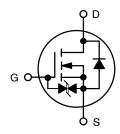
#### **Applications**

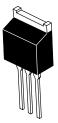
- LCD / LED TV
- Lighting
- Charger / Adapter



# ON Semiconductor®

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IPAK3 CASE 369AR

#### **ORDERING INFORMATION**

See detailed ordering, marking and shipping information on page 2 of this data sheet.

# **MAXIMUM RATINGS** ( $T_C = 25^{\circ}C$ unless otherwise noted)

Symbol	Parameter		Value	Unit	
V <sub>DSS</sub>	Drain-to-Source Voltage		600	V	
V <sub>GSS</sub>	Gate-to-Source Voltage		±25	V	
I <sub>D</sub>	Drain Current	Continuous (T <sub>C</sub> = 25°C)	4	Α	
		Continuous (T <sub>C</sub> = 100°C)	2.4	1	
I <sub>DM</sub>	Drain Current	urrent Pulsed (Note 1)		Α	
E <sub>AS</sub>	Single Pulse Avalanche Energy (Note 2)		216	mJ	
I <sub>AR</sub>	Avalanche Current (Note 1)		4	Α	
E <sub>AR</sub>	Repetitive Avalanche Energy (Note 1)		8.3	mJ	
dv/dt	Peak Diode Recovery (Note 3)		10	V/ns	
$P_{D}$	Power Dissipation	T <sub>C</sub> = 25°C	83	W	
		Derate Above 25°C	0.7	W/°C	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature Range		-55 to +150	°C	
TL	Maximum Lead Temperature for Soldering Purposes (1/8" from case for 5 seconds)		300	°C	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected. 
1. Repetitive Rating: Pulse width limited by maximum junction temperature. 
2.  $I_{AS} = 4$  A,  $V_{DD} = 50$  V, L = 27 mH,  $R_{G} = 25$   $\Omega$ , starting  $T_{J} = 25^{\circ}C$ . 
3.  $I_{SD} \le 4$  A,  $di/dt \le 200$  A/ $\mu$ s,  $V_{DD} \le BV_{DSS}$ , Starting  $T_{J} = 25^{\circ}C$ .

#### THERMAL CHARACTERISTICS

Symb	Parameter Parameter	Value	Unit
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case, Max.	1.5	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient, Max.	90	

# PACKAGE MARKING AND ORDERING INFORMATION

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantity
FDU5N60NZTU	FDU5N60NZ	IPAK	Tube	N/A	N/A	75 units

# **ELECTRICAL CHARACTERISTICS** (T<sub>C</sub> = 25°C unless otherwise specified)

Symbol	Parameter	Test Condition	Min	Тур	Max	Unit
OFF CHARA	CTERISTICS			•	•	•
BV <sub>DSS</sub>	Drain-to-Source Breakdown Voltage	$I_D = 250 \ \mu\text{A}, \ V_{GS} = 0 \ V, \ T_J = 25^{\circ}\text{C}$	600	_	_	V
$\Delta BV_{DSS}/\Delta T_{J}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, Referenced to 25°C	-	0.6	-	V/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 600 V, V <sub>GS</sub> = 0 V	_	_	50	μΑ
		V <sub>DS</sub> = 480 V, T <sub>C</sub> = 125°C	_	_	100	
I <sub>GSS</sub>	Gate-to-Body Leakage Current	V <sub>GS</sub> = ±25 V, V <sub>DS</sub> = 0 V	_	-	±10	μΑ
ON CHARAC	TERISTICS					
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	3.0	-	5.0	V
R <sub>DS(on)</sub>	Static Drain-to-Source On Resistance	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 2 A	_	1.65	2.00	Ω
9 <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> = 20 V, I <sub>D</sub> = 2 A	_	5	-	S
DYNAMIC CI	HARACTERISTICS					
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V, f = 1 MHz	_	450	600	pF
C <sub>oss</sub>	Output Capacitance		-	50	65	
C <sub>rss</sub>	Reverse Transfer Capacitance		_	5	7.5	1
Q <sub>g(tot)</sub>	Total Gate Charge at 10 V	V <sub>DS</sub> = 400 V, I <sub>D</sub> = 4 A, V <sub>GS</sub> = 10 V (Note 4)	-	10	13	nC
$Q_{gs}$	Gate-to-Source Gate Charge		-	2.5	_	]
$Q_{gd}$	Gate-to-Drain "Miller" Charge		_	4	_	
SWITCHING	CHARACTERISTICS					
t <sub>d(on)</sub>	Turn-On Delay Time	V <sub>DD</sub> = 250 V, I <sub>D</sub> = 4 A,	_	15	40	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{GS} = \overline{10} \text{ V}, R_G = 2\overline{5} \Omega \text{ (Note 4)}$	_	20	50	1
t <sub>d(off)</sub>	Turn-Off Delay Time		_	35	80	
t <sub>f</sub>	Turn-Off Fall Time		_	20	50	
DRAIN-SOU	RCE DIODE CHARACTERISTICS					
I <sub>S</sub>	Maximum Continuous Drain to Source Diode Forward Current		_	_	4	Α
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current		-	-	16	
$V_{SD}$	Drain to Source Diode Forward Voltage	V <sub>GS</sub> = 0 V, I <sub>SD</sub> = 4 A	-	-	1.4	V
t <sub>rr</sub>	Reverse Recovery Time	$V_{GS} = 0 \text{ V, } I_{SD} = 4 \text{ A,}$ $dI_F/dt = 100 \text{ A/}\mu\text{s}$	-	230	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge			0.9	1	μС

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

4. Essentially independent of Operating Temperature Typical Characteristics.

#### **TYPICAL CHARACTERISTICS**

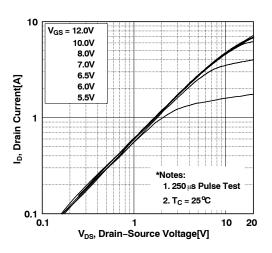


Figure 1. On-Region Characteristics

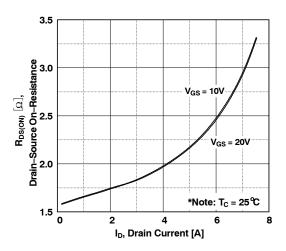


Figure 3. On–Resistance Variation vs. Drain Current and Gate Voltage

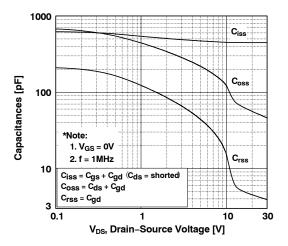
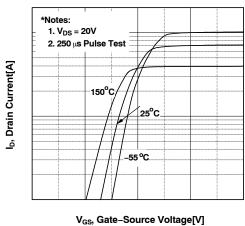


Figure 5. Capacitance Characteristics



vas, date course voltage[v]

Figure 2. Transfer Characteristics

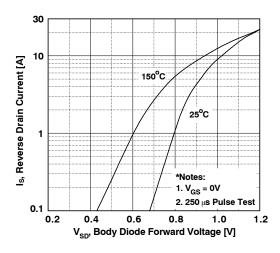


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

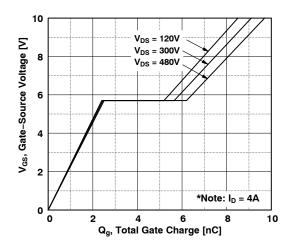


Figure 6. Gate Charge Characteristics

#### **TYPICAL CHARACTERISTICS**

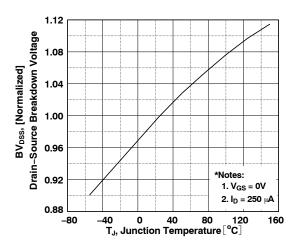


Figure 7. Breakdown Voltage Variation vs. Temperature

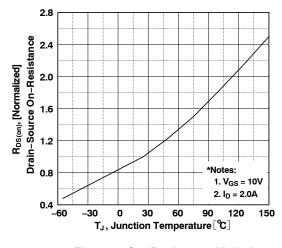


Figure 8. On–Resistance Variation vs. Temperature

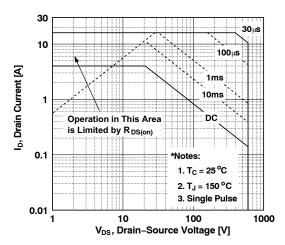


Figure 9. Maximum Safe Operating Area

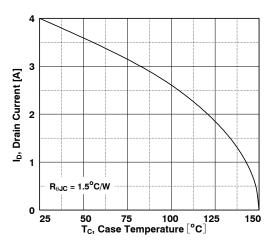


Figure 10. Maximum Drain Current vs. Case Temperature

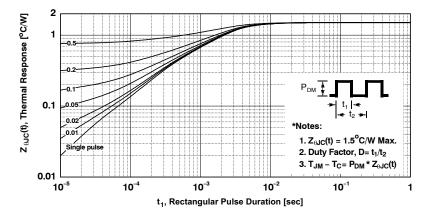


Figure 11. Transient Thermal Response Curve

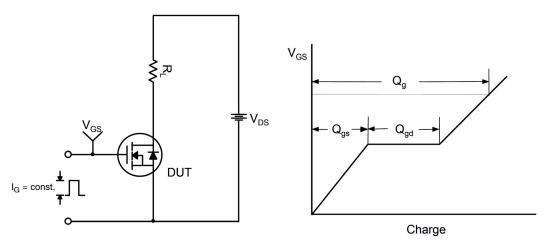


Figure 12. Gate Charge Test Circuit & Waveform

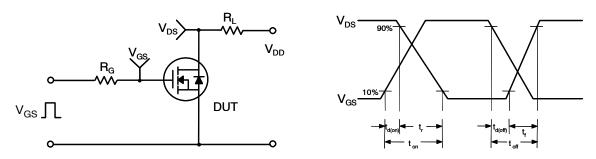


Figure 13. Resistive Switching Test Circuit & Waveforms

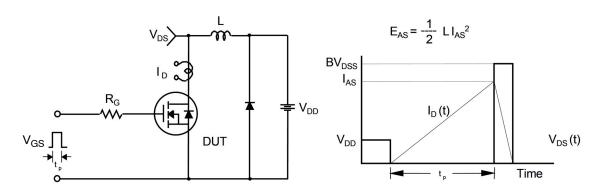
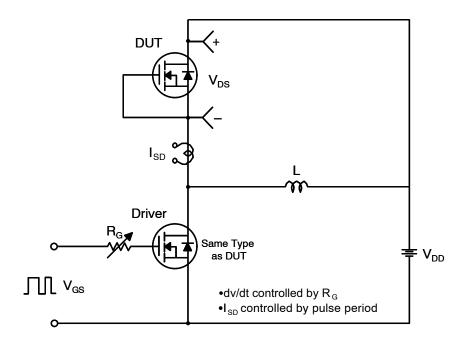


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms



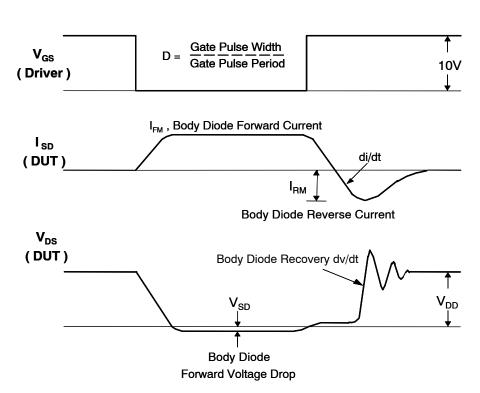
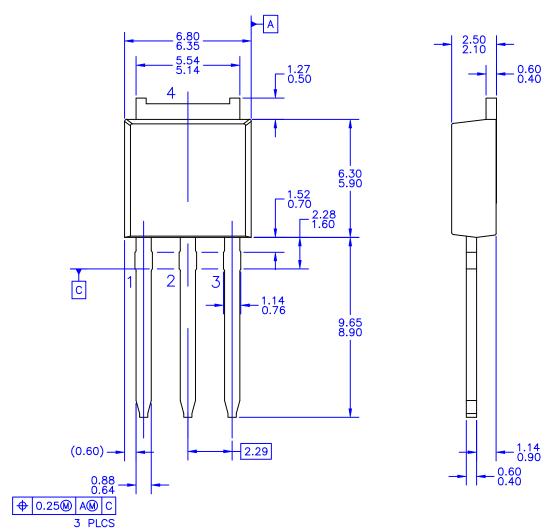


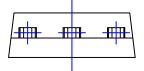
Figure 15. Peak Diode Recovery dv/dt Test Circuit & Waveforms

#### **PACKAGE DIMENSIONS**

#### DPAK3 (IPAK) CASE 369AR ISSUE O



NOTES: UNLESS OTHERWISE SPECIFIED



- A) ALL DIMENSIONS ARE IN MILLIMETERS.
- B) THIS PACKAGE CONFORMS TO JEDEC, TO-251, ISSUE C, VARIATION AA, DATED SEP 1988.
- C) DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.

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